


| | | | |
|-----------------------------------|---|--|-------------|
| Notice of References Cited | Application/Control No. 10/025,465 | Applicant(s)/Patent Under Reexamination KAMBE, TOSHIYUKI | |
| | Examiner Tina M Lin  | Art Unit 2874 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-5,483,609 | 01-1996 | Nakaya, Ken-ichi | 385/29 |
| | B | US-6,400,881 b1 | 06-2002 | Seino et al. | 385/130 |
| | C | US-5,193,130 | 03-1993 | Nishiwaki et al. | 385/14 |
| | D | US-2002/0123158 a1 | 09-2002 | Murai, Masami | 438/3 |
| | E | US-5,455,876 | 10-1995 | Hopfer et al. | 385/2 |
| | F | US-5,506,919 | 04-1996 | Roberts, David A. | 385/1 |
| | G | US-6,377,716 b1 | 04-2002 | Veldhuis et al. | 385/1 |
| | H | US-6,107,116 | 08-2000 | Kariya et al. | 438/87 |
| | I | US-6,211,993 b1 | 04-2001 | Wang et al. | 359/260 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.